

One Hundred Watt Operation Demonstration of HVM LPP-EUV Source

2014 International Workshop on EUV Lithography

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*CTO & Executive Vice President
Gigaphoton Inc.*

AGENDA

- Key Technical Points of EUV LPP Light Source
 - » Issues of EUV Light Source Power
 - » History of LPP Technology
- Gigaphoton's LPP Light Source Concept
 - » Droplet Generator
 - » Pre-pulse Technology
 - » Collector Mirror and IR Reduction Technology
 - » Debris Mitigation Technology
- Gigaphoton's High Power LPP Light Source System Development
 - » Debris Mitigation Technology Update
 - » Output Power Update
- Power-up Scenarios of HVM EUV Light Sources
- Summary

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Technical Issues of EUV Lithography

EUV light transmittance is only 2% with 11 reflection mirror systems

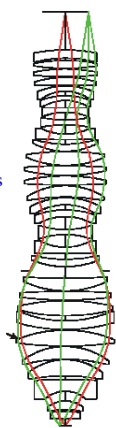
SiO₂, CaF₂
>30 lenses and few mirrors

NA=0.85-1.35

Imaging (30)
 $0.98^{30}=0.55$

Imaging (30)
+
Illumination (20)

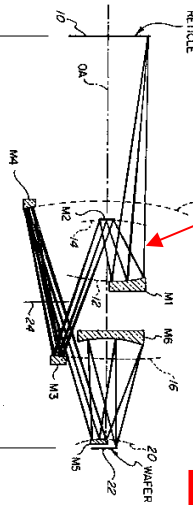
$0.98^{50}=0.36$



DUV

Mask

Wafer



EUV

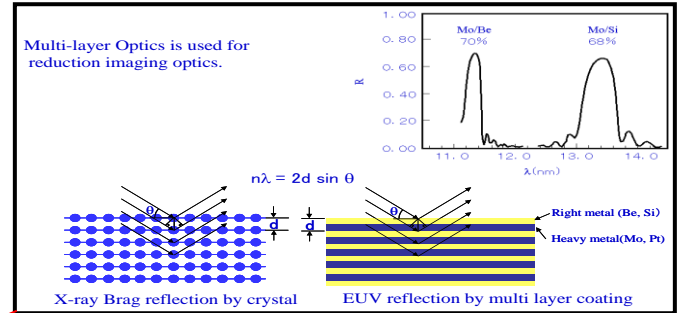
Mo/Si multilayer
6-8 mirrors

NA=0.25-0.35

Imaging (6)
 $0.70^6=0.11$

Imaging (6)
+
Illumination (11)

$0.70^{11}=0.02$



70% reflection

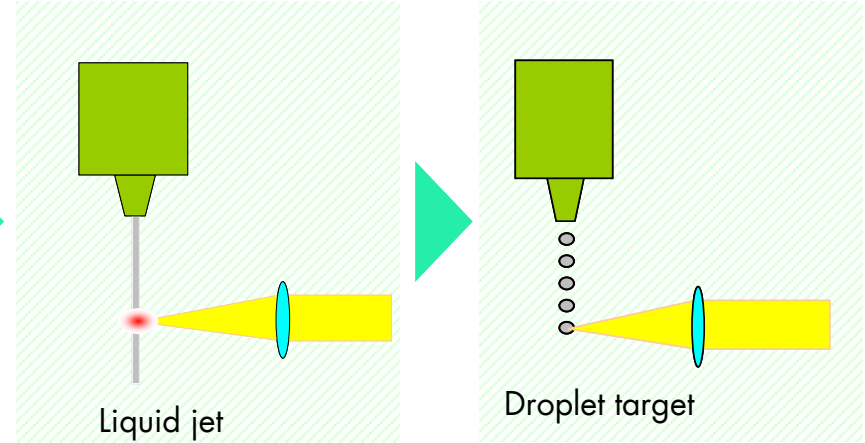
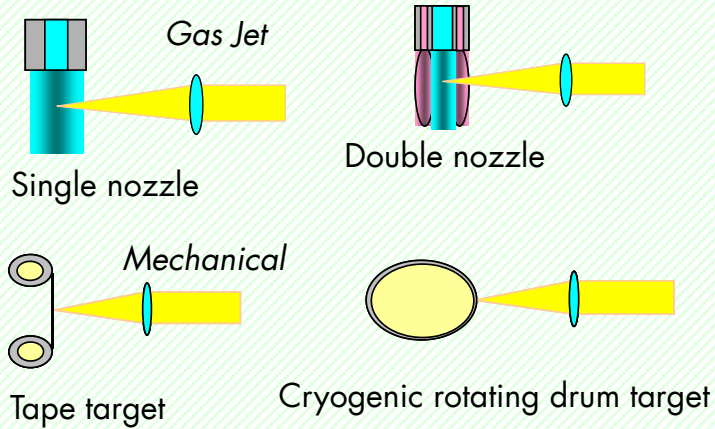
High power light sources for HVM exposure tools is the key issue

Demand is > 250W
at first stage HVM

History of LPP Source Development in Japan

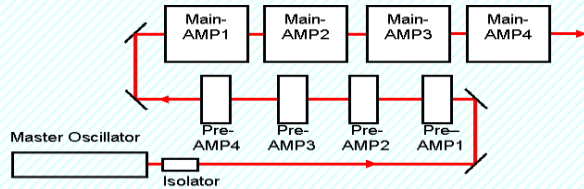
Target

Target Technologies

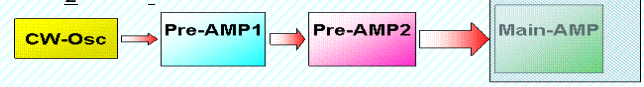


Laser

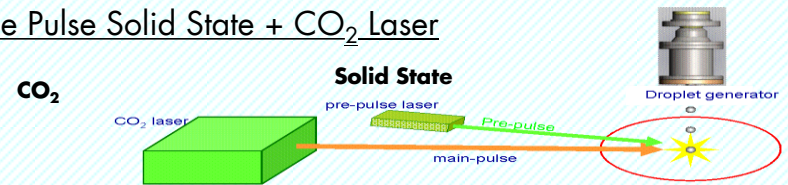
Solid State Laser



CO₂Laser



Double Pulse Solid State + CO₂ Laser

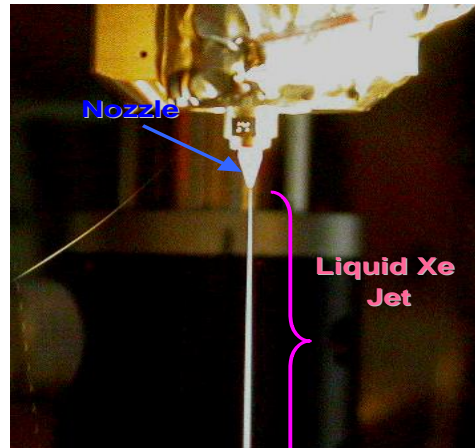


History of LPP Source Development in Japan

Liquid Xe jet target experiment with YAG laser driver

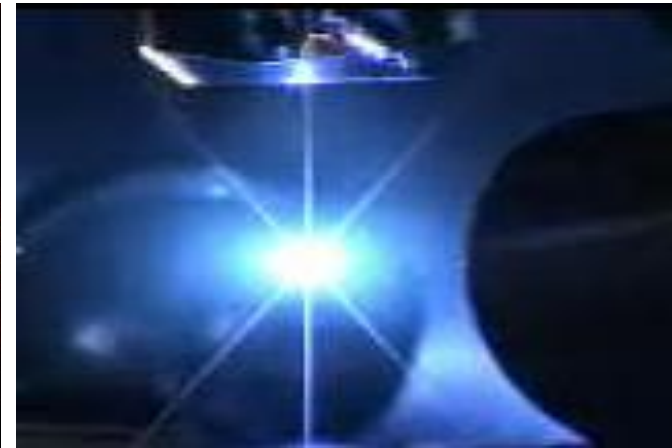


Liquid Xenon Jet System



Xe Jet

Velocity : 30 m/s
Stability σ : 10 μ m@10mm

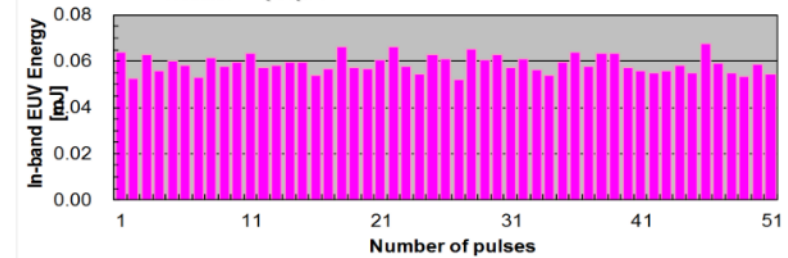
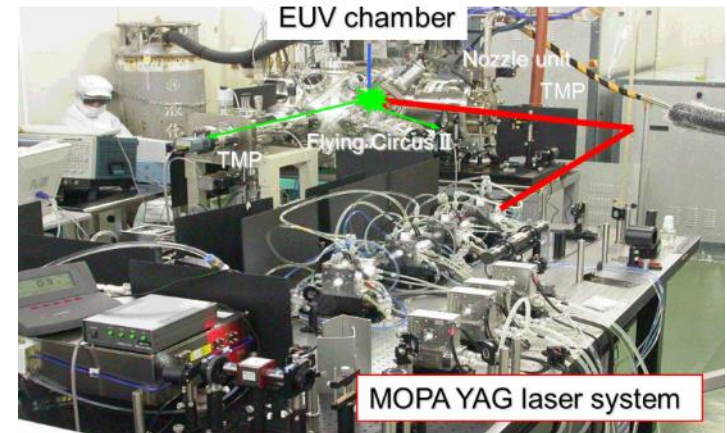
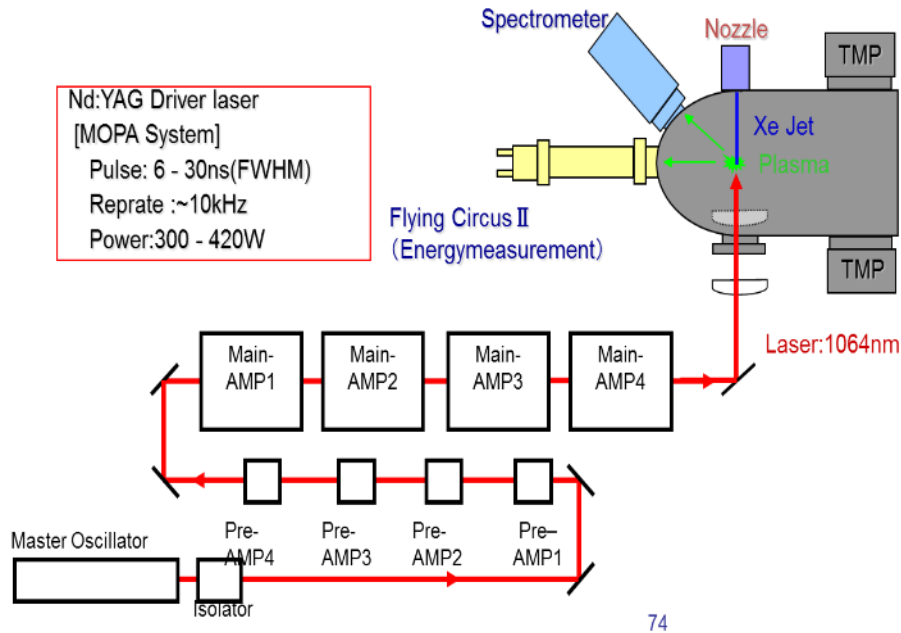


Xe Jet and Plasma

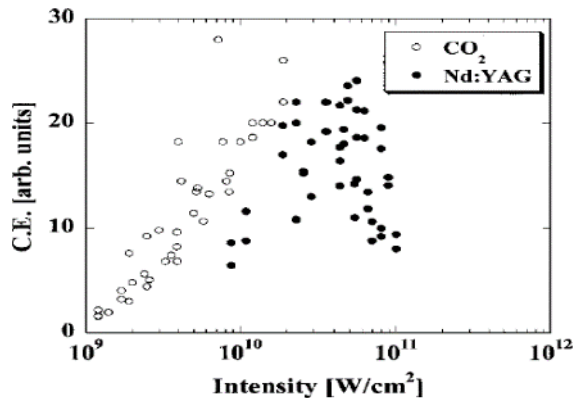
Xe Temperature : 160K - 190K
Xe Pressure : < 5MPa

History of LPP Source Development in Japan

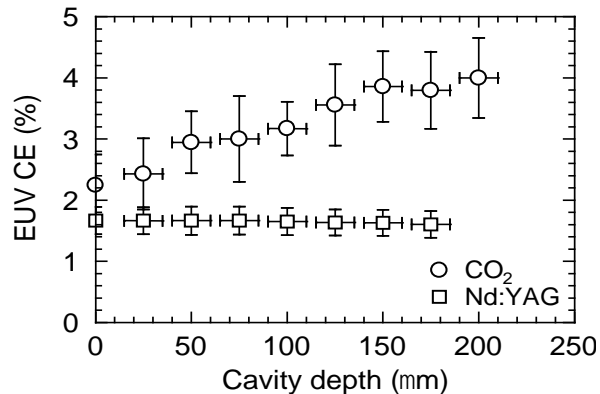
LPP EUV light generation test (2004) with Xe Jet + YAG laser system



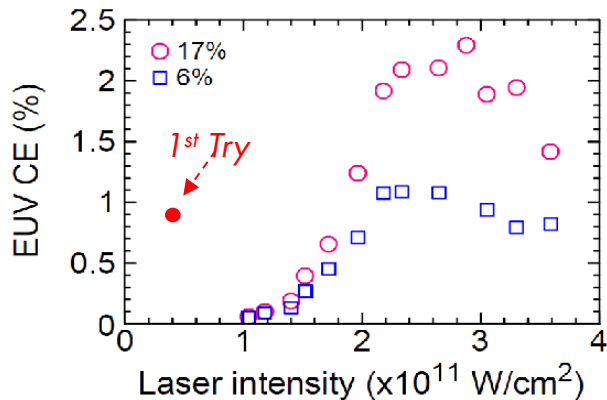
History of LPP Source Development in Japan



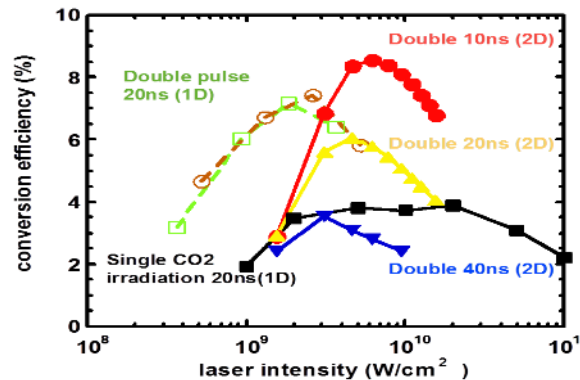
Kyusyu Univ. /
H. Tanaka et al.
/ Appl. Phys.
Lett. 87,041503
(2005)



EUV conversion
efficiency (solid
target)
demonstrated in
EUVA (2005)



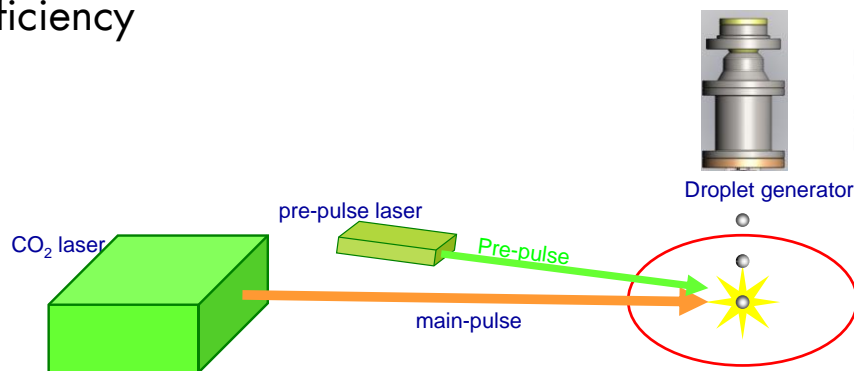
Miyazaki Univ. / T.
Higashiguchi et al.
/ SPIE
Microlithography
2006, 6151-146
(2006)



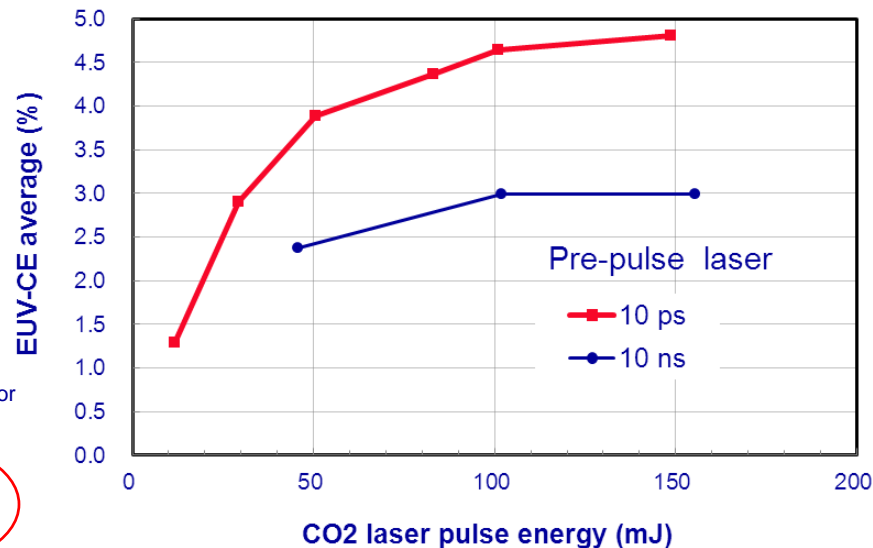
EUV conversion
efficiency
simulation by
Osaka Univ.
team (2006)

History of LPP Source Development in Japan

- Based on basic physical consideration and experiments, Gigaphoton has chosen to adopt the pre-pulse technology since 2009
- In 2012 Gigaphoton discovered that shortening the pre-pulses duration dramatically enhance the conversion efficiency



CO₂ pulse energy vs. EUV-CE

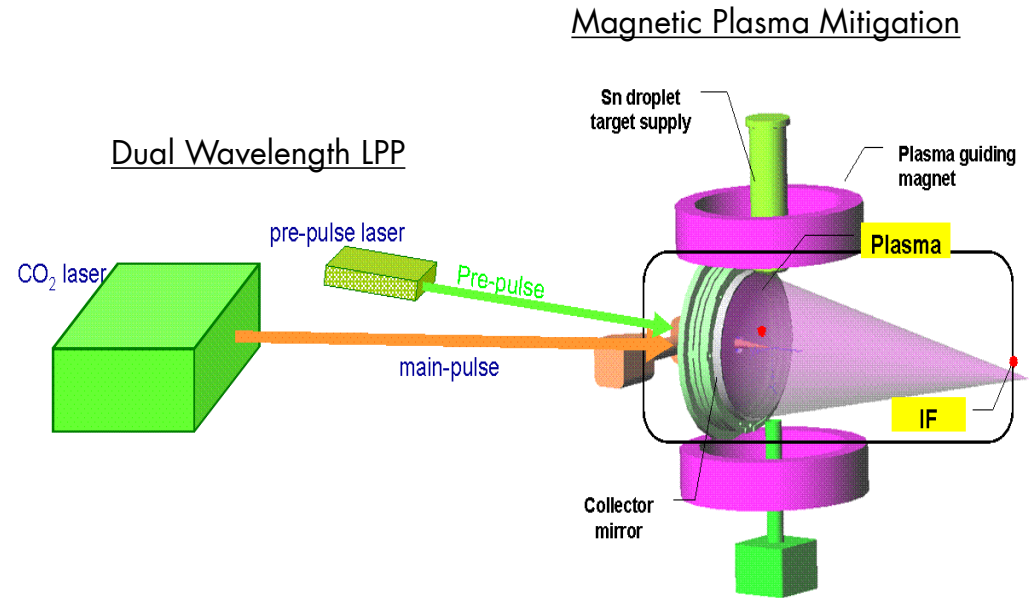


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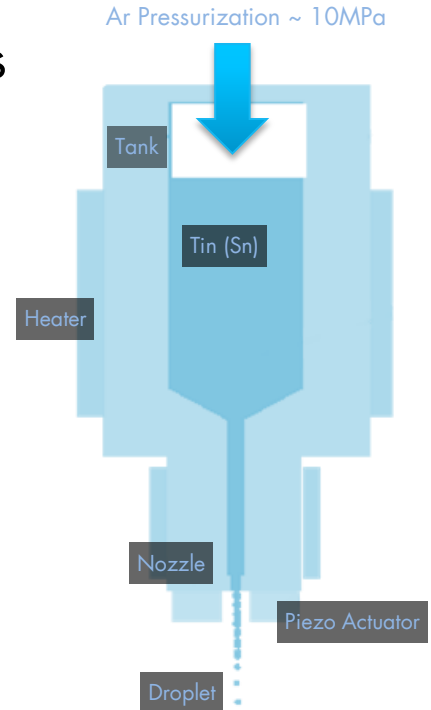
Gigaphoton's LPP Light Source Concept

1. High ionization rate and CE EUV Sn plasma generated by CO₂ and solid laser dual shooting
2. Hybrid CO₂ laser system with short pulse high repetition rate oscillator and commercial cw-amplifiers
3. Accurate shooting control with droplet and laser beam control
4. Sn debris mitigation with a super conductive magnetic field
5. High efficient out of band light reduction with grating structured C1 mirror



Droplet Generator Technology

- The **Droplet Generator** is one of the key technologies for achieving HVM level EUV light sources
- Requirement for droplet generator
 - » Size of droplet is **20 μm**
 - Smaller droplet is better
 - Debris mitigation
 - Longer lifetime of droplet generator
 - Technical barrier is higher
 - Clogging due to smaller nozzle
 - » Stability is **$\pm 20\mu\text{m}$**
 - Short and long term stability is necessarily to achieve stable dose control



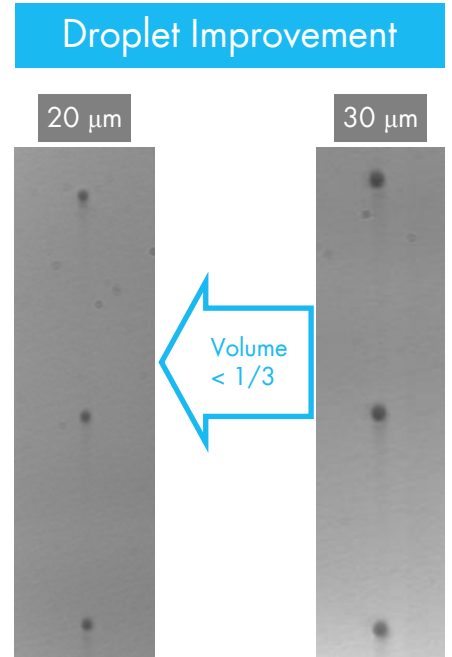
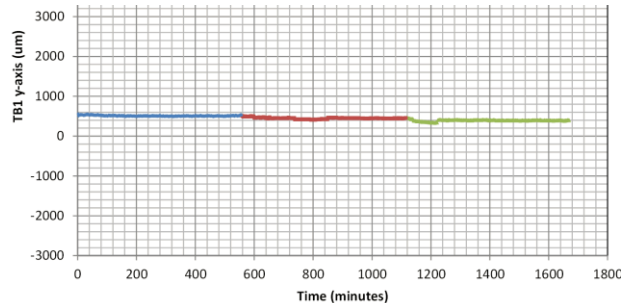
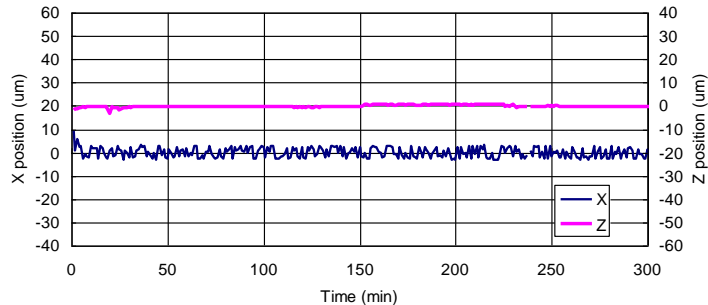
Droplet Generator Technology

Improvements over time:

	2012 Q4	2013 Q2	2014 Q1
Size (Diameter)	30 μm	25 μm	20 μm
Volume	118 pico-liter	65 pico-liter	34 pico-liter
Frequency	100 kHz	200 kHz	100 kHz
Spacing	500 μm	250 μm	480 μm

Droplet Generator Technology

- 100 kHz, 20 μm droplet generation was confirmed
- Short & middle term stability was confirmed
 - » Good margin compare to the target $\pm 20 \mu\text{m}$
 - » No clogging / stability change even with cool down & re-start

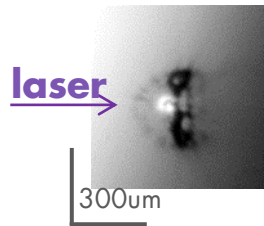


Pre-Pulse Technology

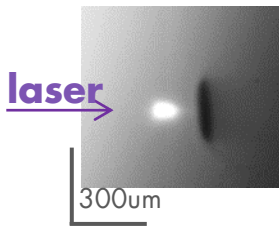
Experiment shows picosecond pre-pulse dramatically enhances ionization rate and CE

Sn Droplet Smash

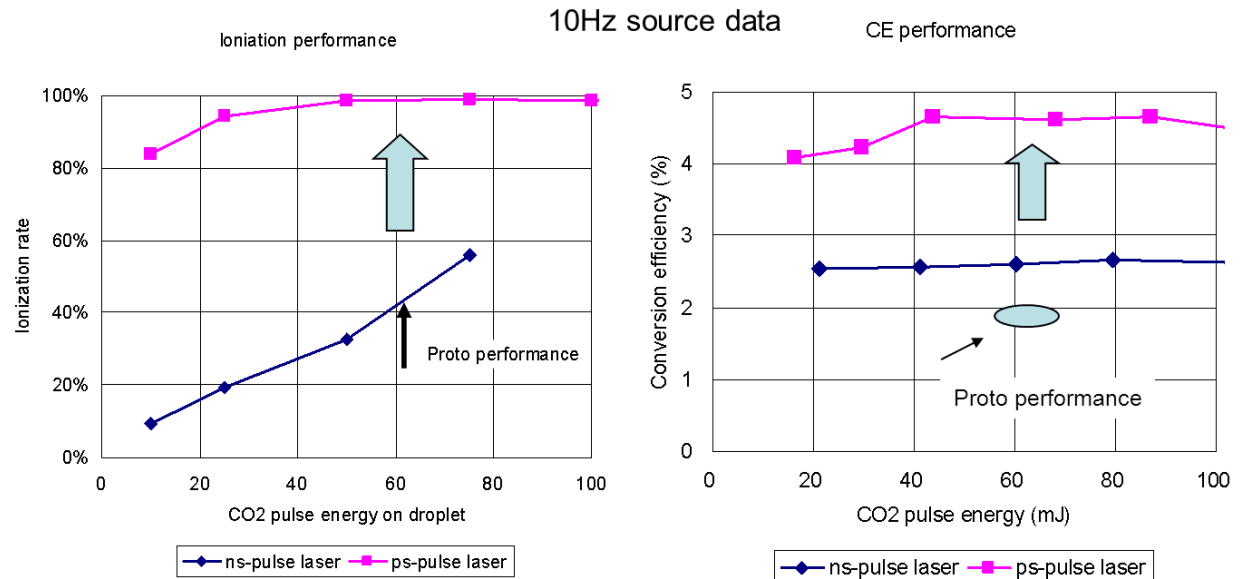
psec Dome like target



nsec Flat disk like target



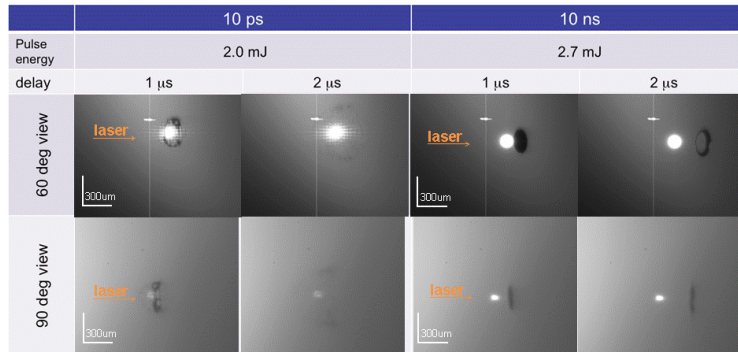
Data in 10 Hz Experimental Device



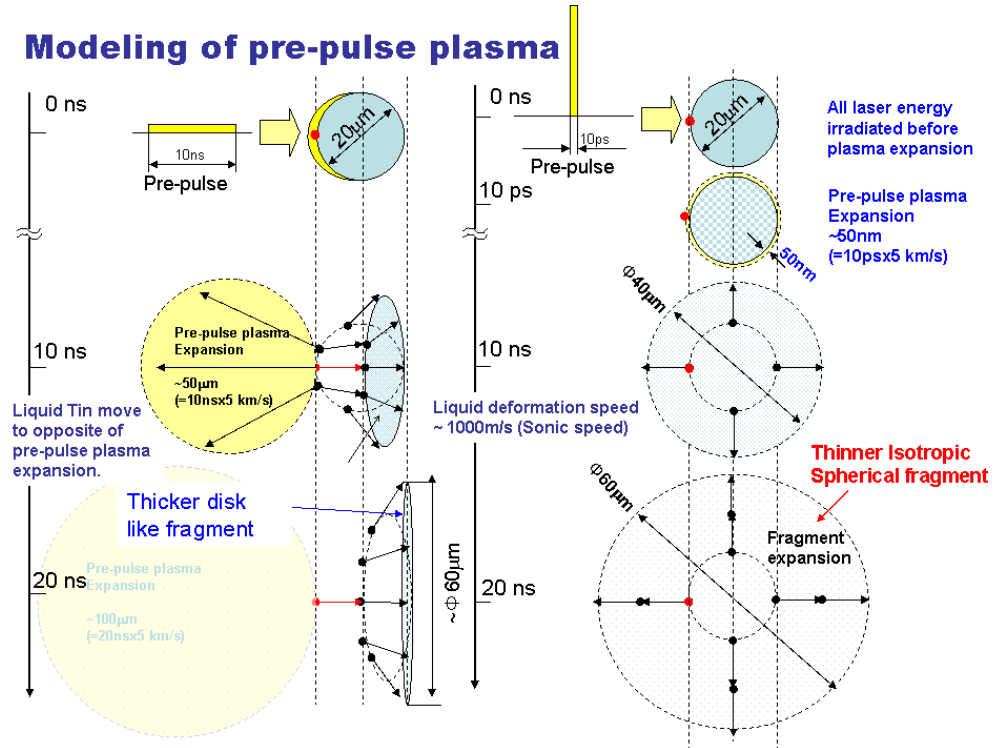
Pre-Pulse Technology

Fragment distribution measurement and modeling

- The mist shape of a picosecond pre-pulse is different from the nanosecond pre-pulse (ps = dome vs. ns=thin disk or ring)
- Fragment distribution could be a key factor for high CE



Modeling of pre-pulse plasma



Debris Mitigation Technology

Gas mitigation method

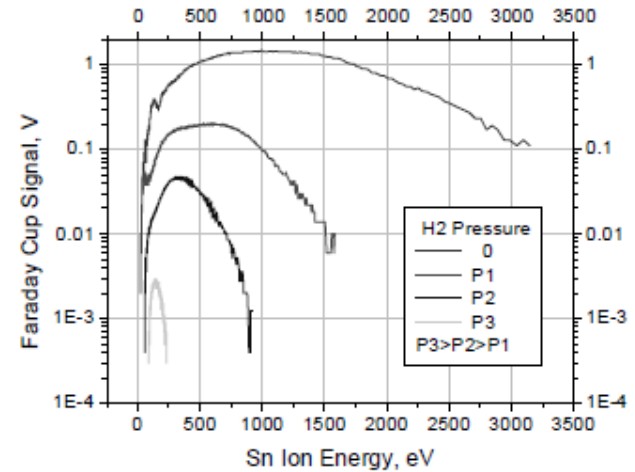
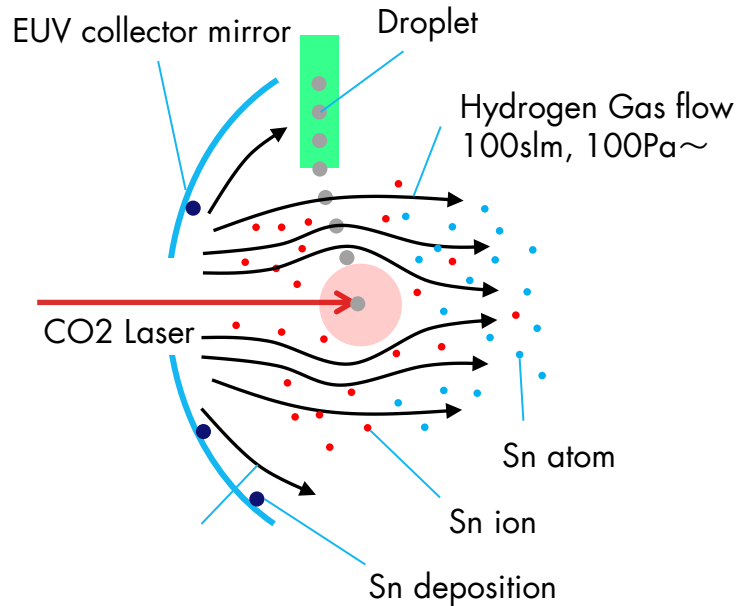
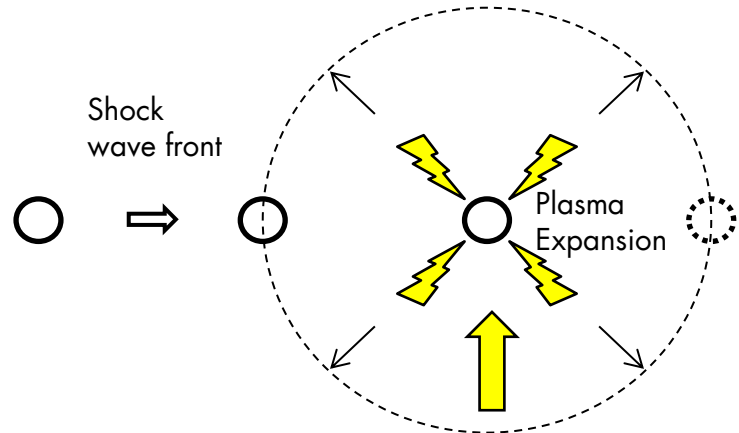


Figure 10: Hydrogen buffer gas pressure vs. ion energy and flux at the location of the collector surface

Proc. of SPIE Vol. 7636 763639 (2010)

Debris Mitigation Technology

Issue with previous gas mitigation techniques



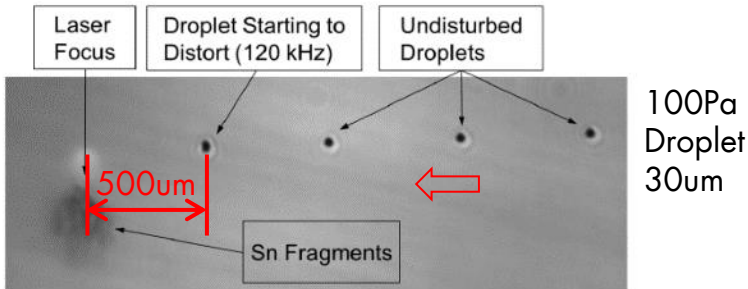
The Vicious Circle of Mitigation and Output Power

Higher Power

Gigaphoton has broken this vicious circle by developing the **Magnetic Debris Mitigation** system

Increase fragment and deposition

Increase Hydrogen pressure to compensate



Proc. of SPIE Vol. 8322 83222N (2012)

Debris Mitigation Technology

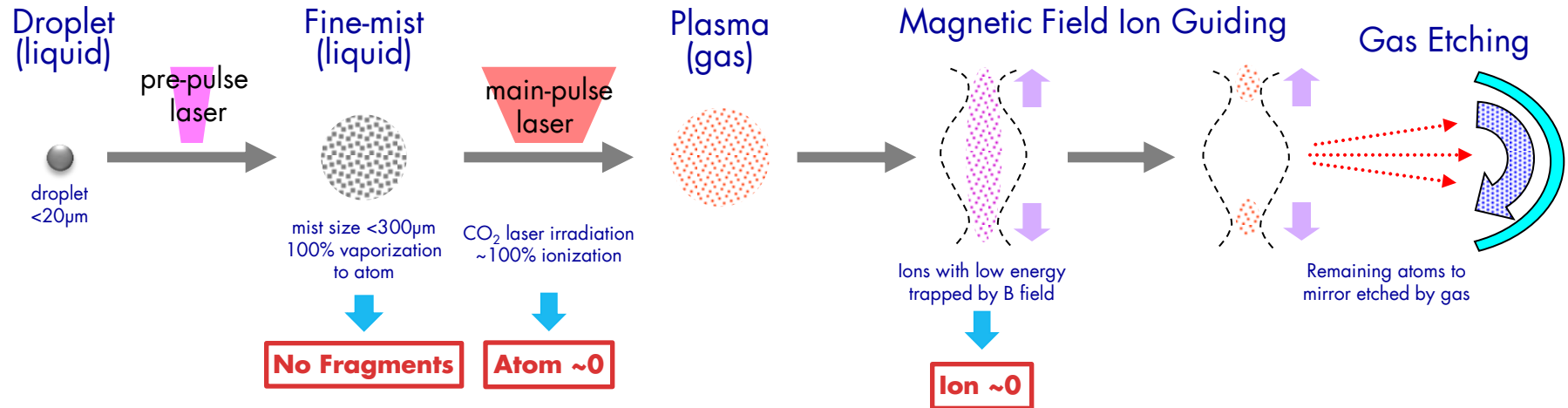
Gigaphoton's Magnetic Debris Mitigation concept

Higher CE and Power

- Optimum wavelength to transform droplets into fine mist
- Higher CE achievement with ideal expansion of the fine mist

Long Life Chamber

- Debris mitigation by magnetic field
- Ionized tin atoms are guided to tin catcher by magnetic field

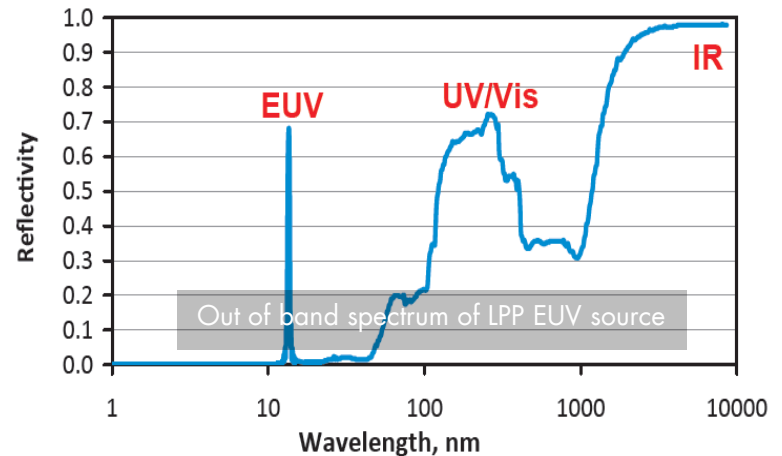
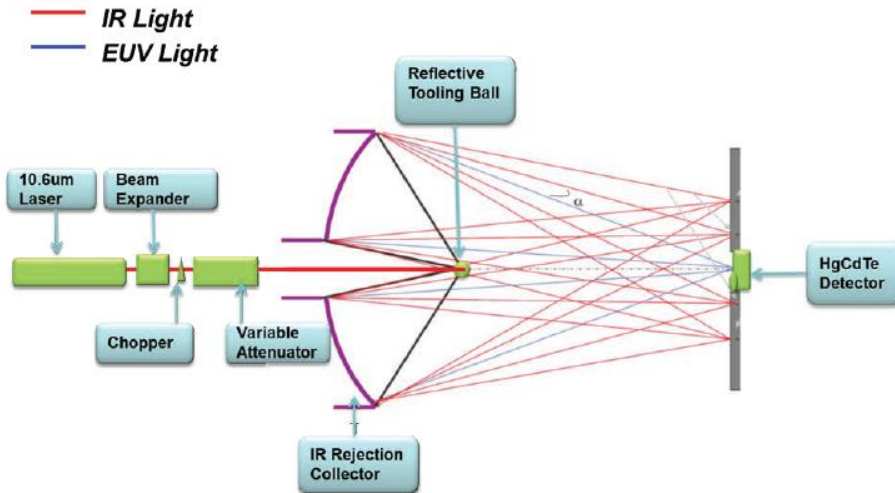


Collector Mirror Technology

Collector Mirror progress

IR Reduction Technology is Advancing

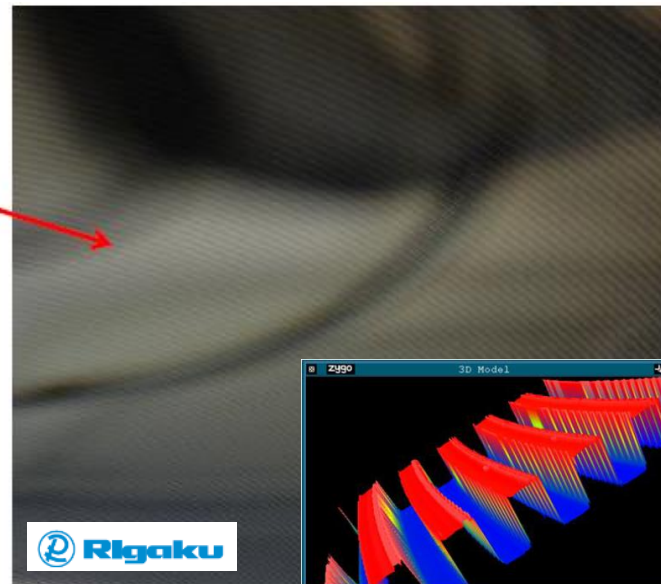
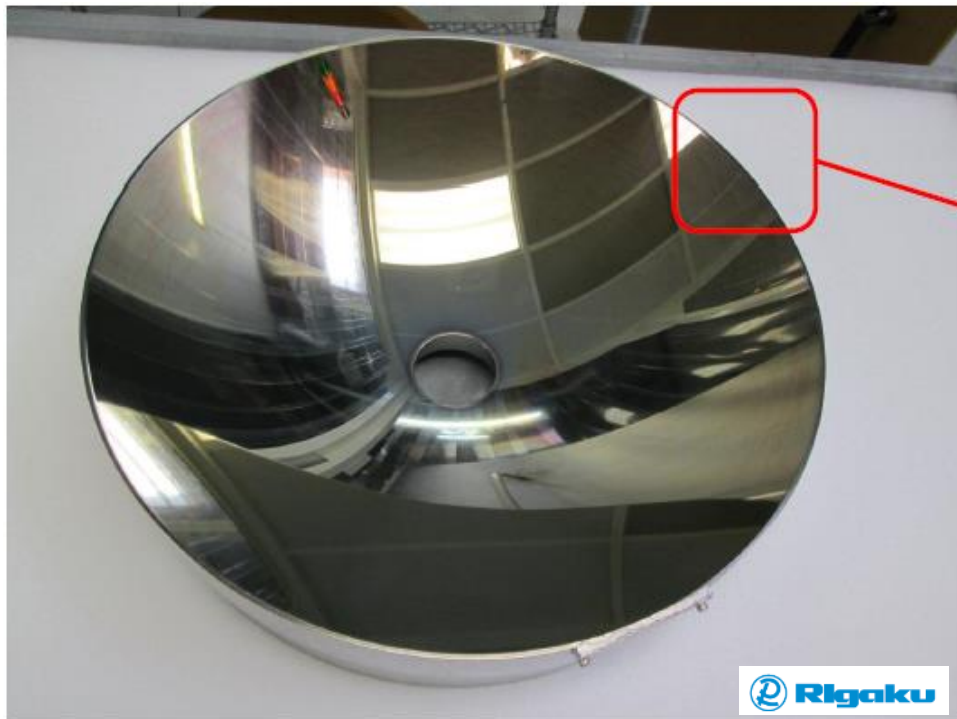
Gigaphoton is developing IR reduction mirror in co-operation with multiple mirror suppliers.



Gigaphoton's Patent Pending IR Reduction Technology

Collector Mirror and IR Reduction Technology

Rigaku succeeded in producing a unique Diffraction Grating Collector Mirror (DGCM)

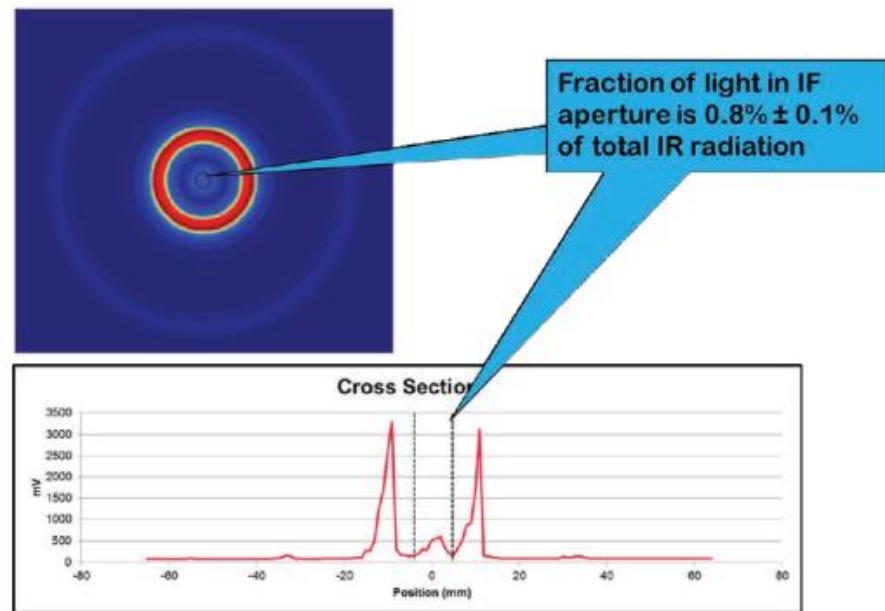
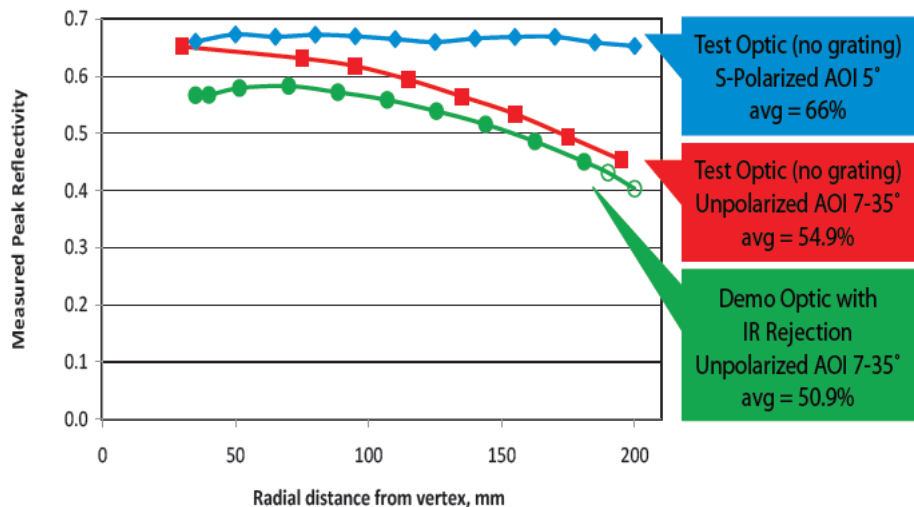


Grating Structure

"International Symposium on EUVL" 6-10 October 2013, Toyama, Japan

Collector Mirror and IR Reduction Technology

- Rigaku demonstrated efficient and dramatic IR reduction by putting gratings on the mirror surface
- Prefabrication test completed
(data is reported EUV symposium 2013 in Toyama)
- Next step is proto type fabrication and evaluation

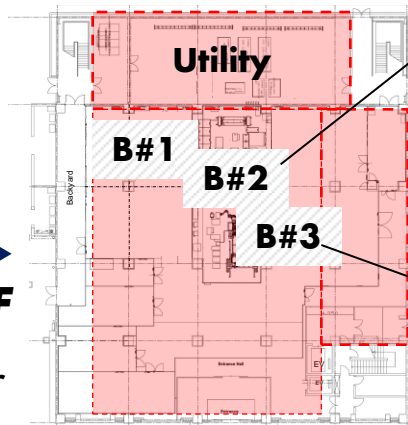
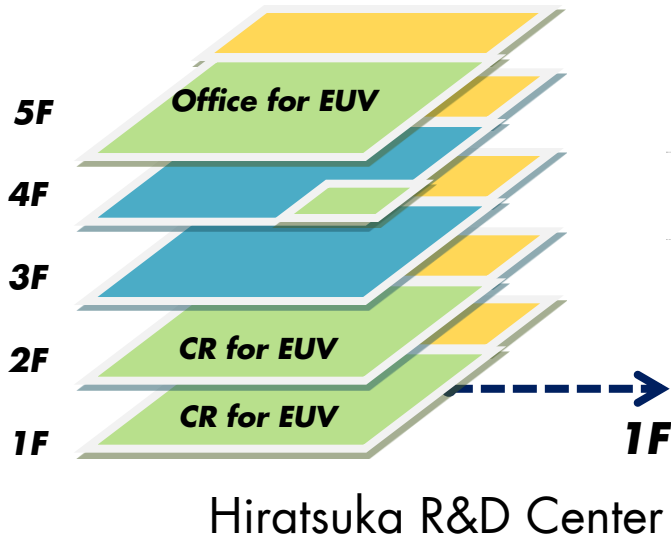


AGENDA

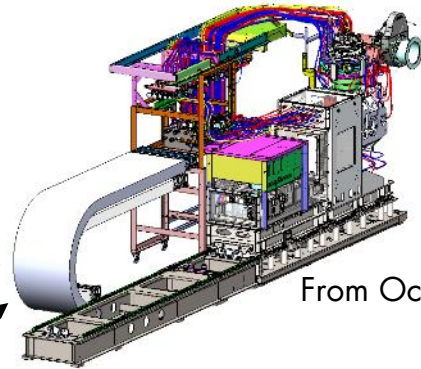
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Proto Systems in Operation

Two proto systems are now operating at Hiratsuka R&D Center clean room

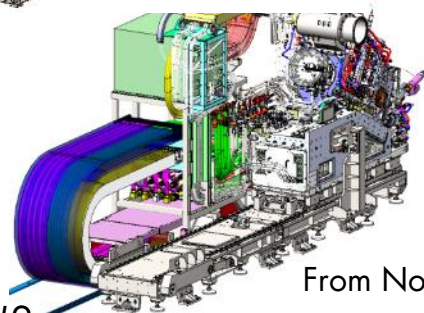


Proto #1
EUV Chamber



From Oct. 2012

Proto #2
EUV Chamber



From Nov. 2013

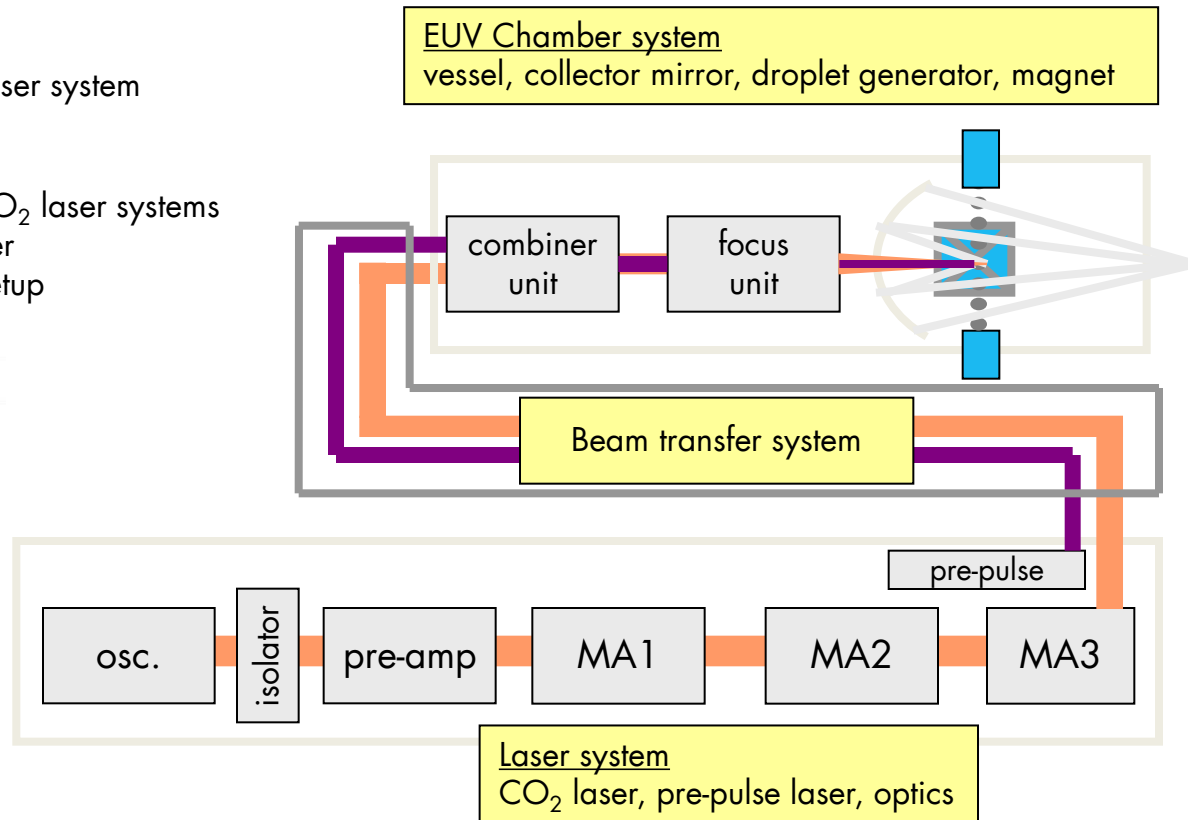
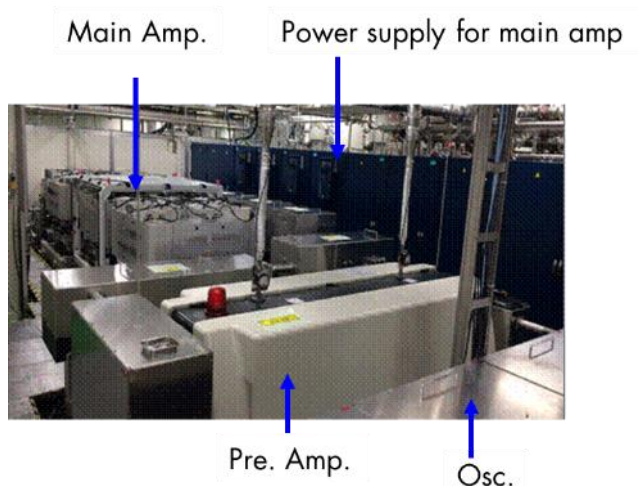
Proto Systems in Operation

Target System Specifications

Operational Specification		Proto #1	Proto #2	Customer Beta Unit
Target Performance	EUV Power	25 W	100 W	250 W
	CE	3%	4%	4%
	Pulse rate	100 kHz	100 kHz	100 kHz
	Output angle	Horizontal	62° upper (matched to NXE)	62° upper (matched to NXE)
	Availability	1 week operation	1 week operation	> 75%
Technology	Droplet generator	20 – 25 μm	20 μm	< 20 μm
	CO2 laser	> 8 kW	> 12 kW	25 kW
	Pre-pulse laser	picosecond	picosecond	picosecond
	Debris mitigation	validation of magnetic mitigation in system	10 days	15 days

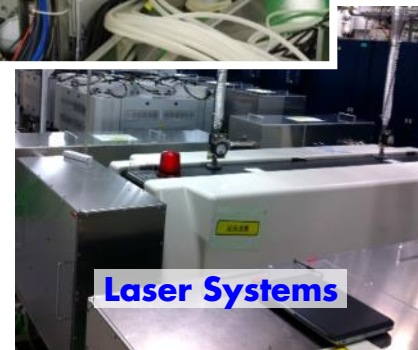
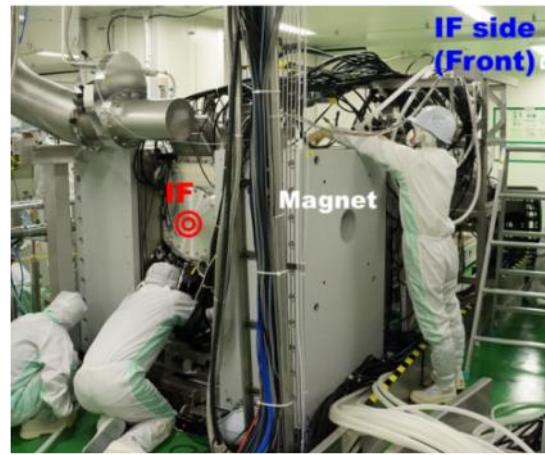
Proto Systems in Operation

- Proto #1
 - » 5 kW CO₂ power by 2 MA CO₂ laser system
 - » Target is > 25 W EUV clean power
- Proto #2
 - » 8 -14 kW CO₂ power by 3 MA CO₂ laser systems
 - » Target is > 100 W EUV clean power
 - » EUV chamber around 60° angle setup



EUV Light Source for Debris Mitigation Testing

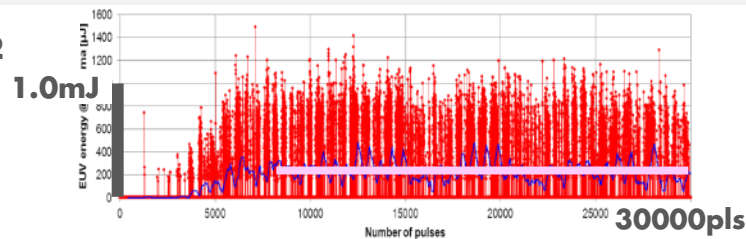
- Proto #1 for Debris mitigation test
 - » Complete system (laser and chamber) is working now
 - » Currently using for mitigation technology development
- Proto #2 for high power development
 - » Assembly and adjustment has completed
 - » The first EUV emission data in January 2014.



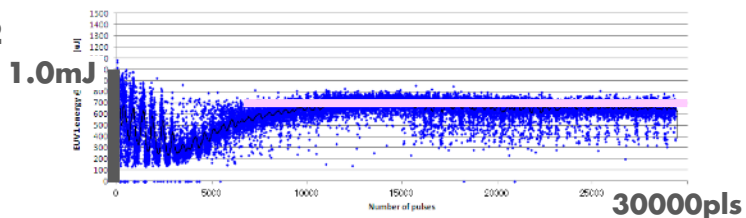
EUV Light Source for Debris Mitigation Testing

In-burst power performance improvements on Proto #1

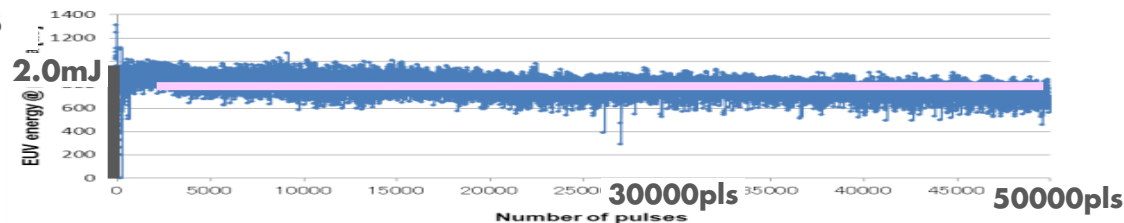
Nov. 2012



Mar. 2012



Dec. 2013



Shooting control and stabilization A

4.3W*, 100 kHz

6.5W*, 50 kHz

Shooting control and stabilization B
Improve pre-pulse laser

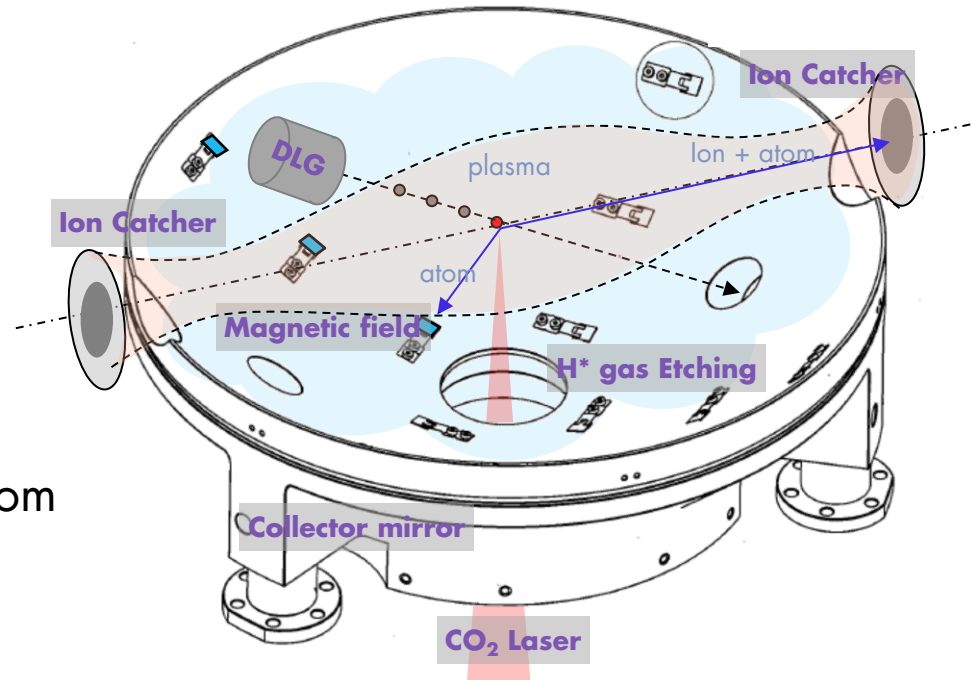
30W*, 100 kHz
CO₂ laser power = 5 kW
ON/OFF = 0.5s/0.5s
Duty = 50%, CE = 3.0%

* EUV Clean power @I/F

EUV Light Source for Debris Mitigation Testing

Gigaphoton's unique magnetic field + gas etching technology

- The collector mirror lifetime (i.e. debris mitigation technology) is one of the key items for reducing cost of consumables for HVM
- Gigaphoton's unique technology for debris mitigation:
 - » Magnetic field to catch Sn ion/atom
 - » H* gas to etch out Sn atom

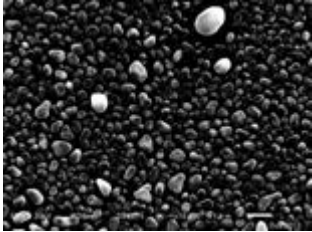
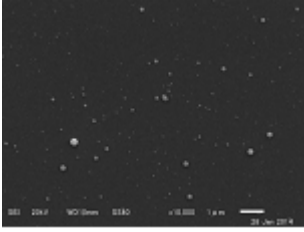


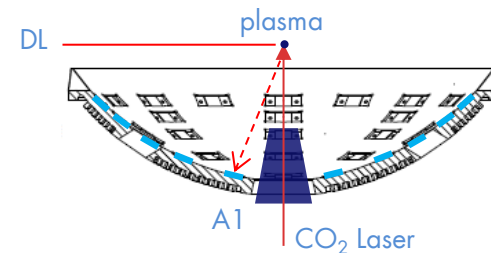
EUV Light Source for Debris Mitigation Testing

First results with 20 μm droplets

Promising result with 20 μm droplet has been confirmed

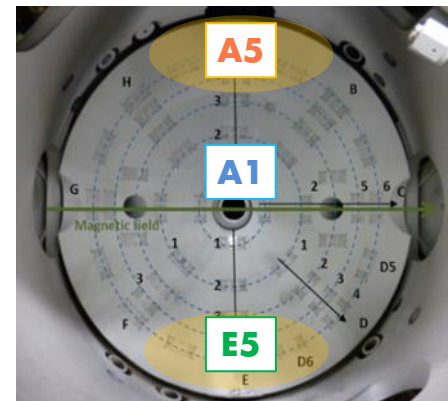
- ✓ Sn deposition rate drastically improved toward 1/5 compared to 25 μm droplets
- ✓ With shooting error improvement, deposition rate is expected to be very small

	25 μm Droplet	20 μm Droplet
Pulse number	152 Mpls	80 Mpls
H ₂ pressure	15 Pa	15 Pa
EUV Energy (3 σ)	23.3%	73.4%
A1 sample Center of collector mirror (SEM x10,000)		
Sn deposition rate	0.5nm/Mpls	0.1nm/Mpls



EUV Light Source for Debris Mitigation Testing

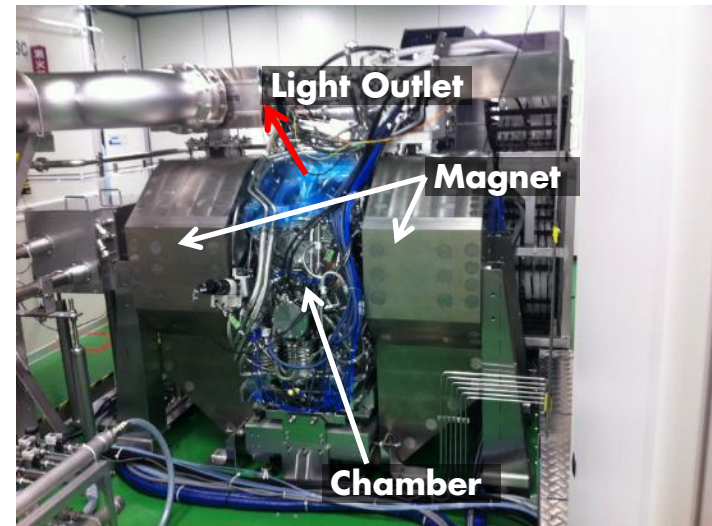
	2013 Oct	2014 Jan	2014. Apr	2014 May
A1 sample (SEM x10,000) <i>Center</i>			0.075nm/Mpls	0.03nm/Mpls
E5 sample (SEM x1,000) <i>Lower</i>			1.1 nm/Mpls	0.8nm/Mpls
A5 sample (SEM x1,000) <i>Upper</i>			0.16nm/Mpls	0.024nm/Mpls



High Power EUV Light Source

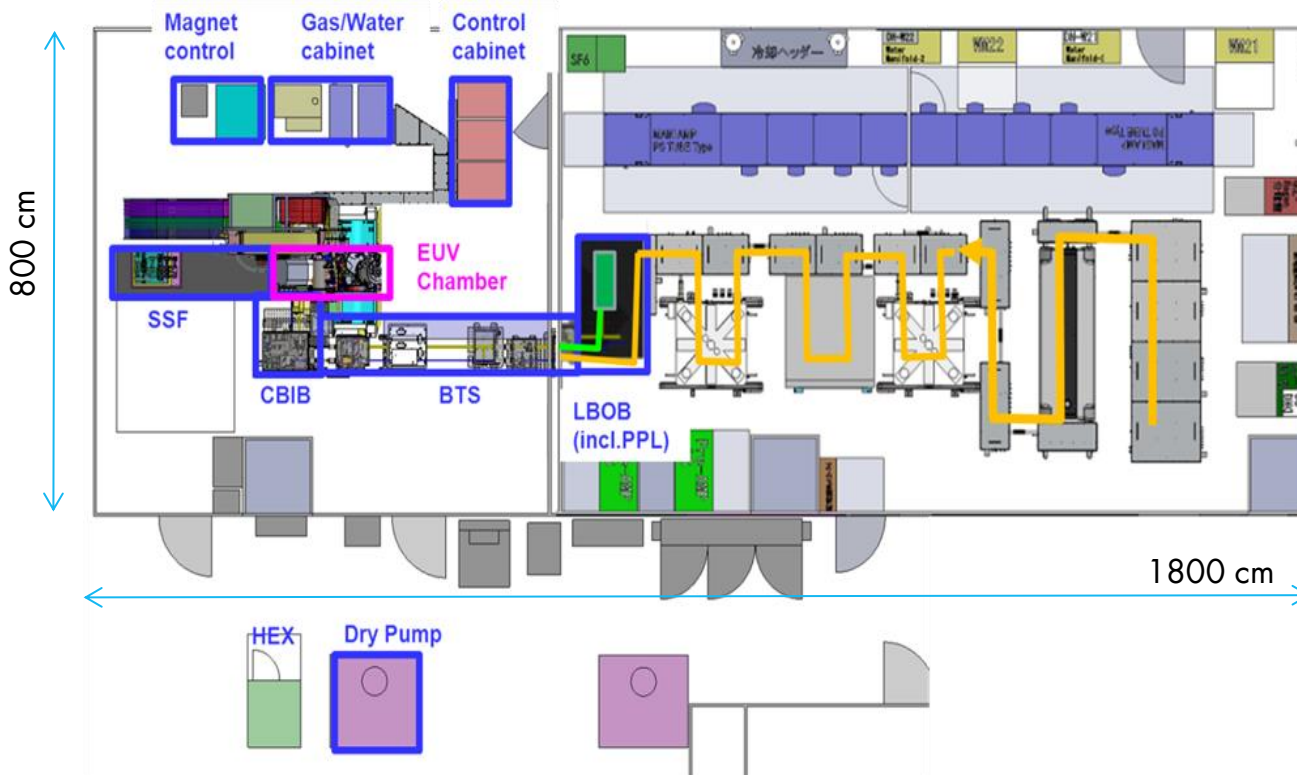
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 - » Currently using for mitigation technology development

- Proto #2 for high power development
 - » Assembly and adjustment is completed
 - » First EUV emission data on January 2014



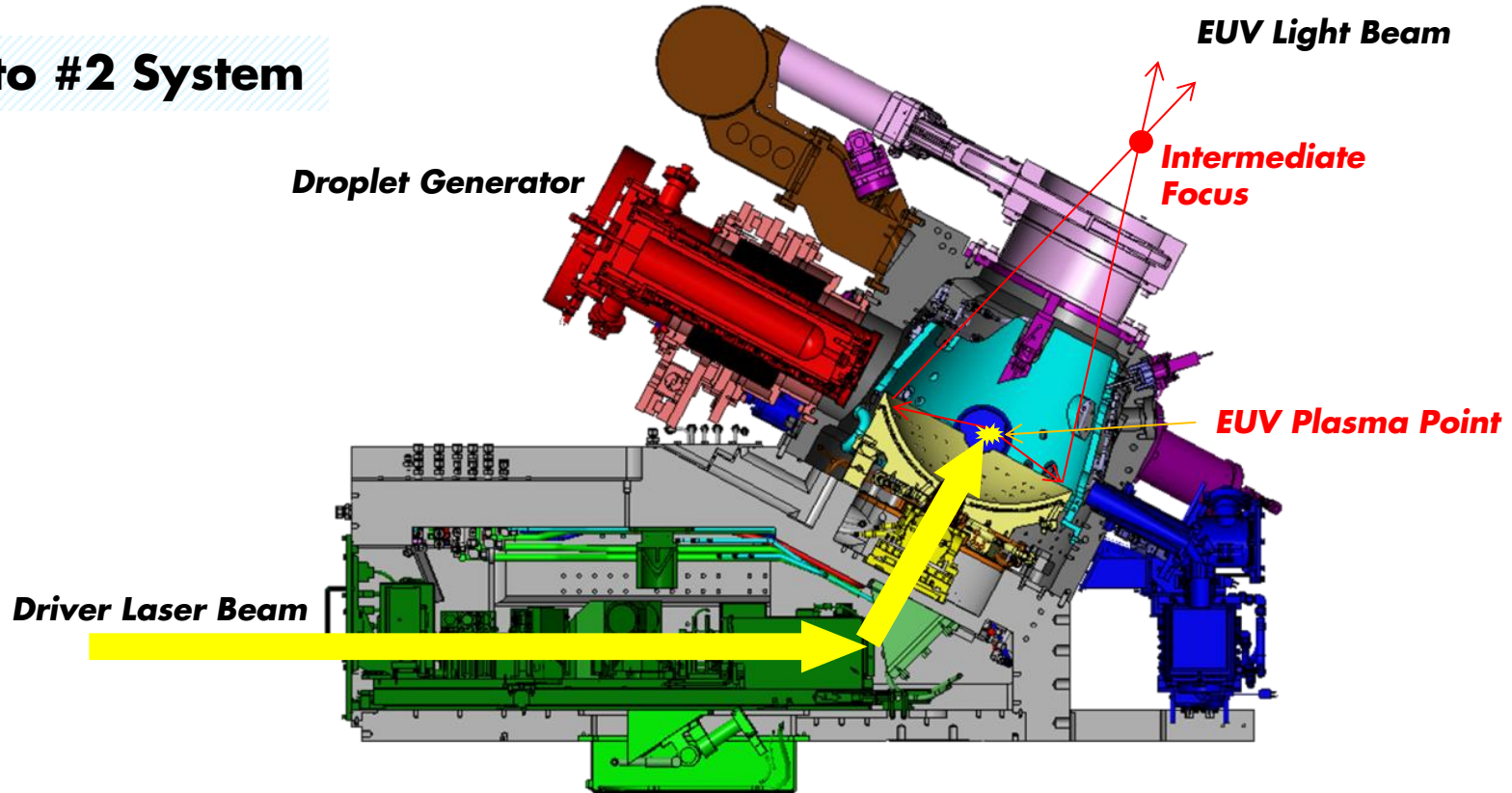
High Power EUV Light Source

The layout



High Power EUV Light Source

Proto #2 System



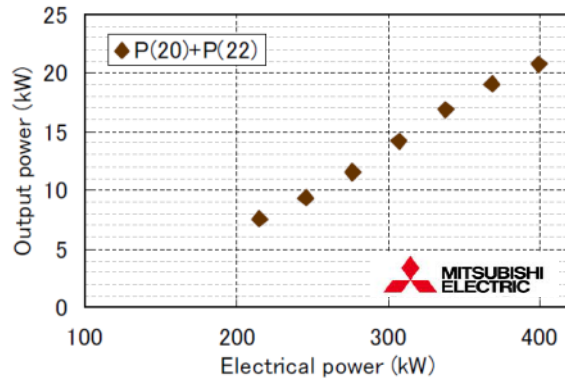
High Power EUV Light Source

Amplification Test @ Mitsubishi Electric (2013)

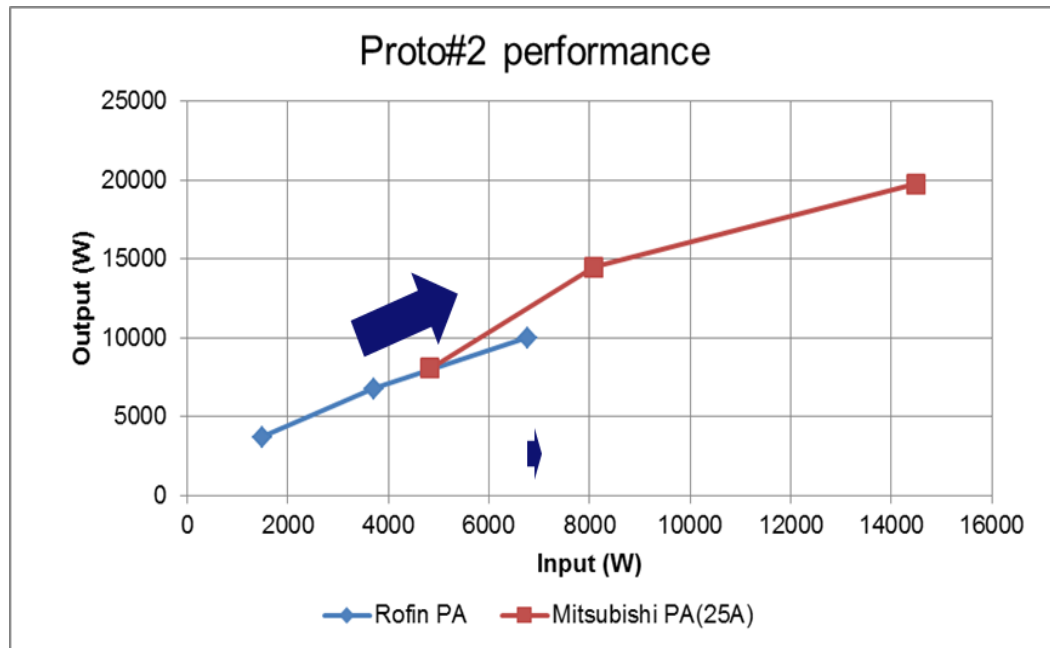
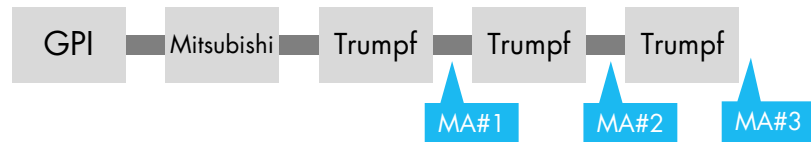


EUV power >100W @ I/F clean trial status

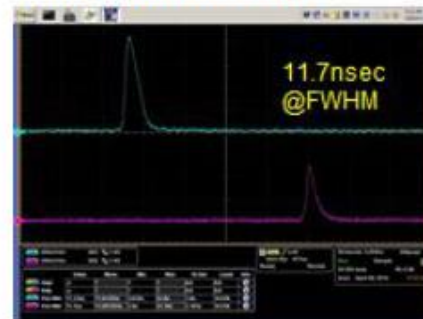
- ✓ 1st pre-amplifier installation is completed
- ✓ Driver laser system test is completed (>12kW OK)
- ✓ Laser shooting system test is ready.
- ✓ EUV test ongoing (collecting first high power data now)



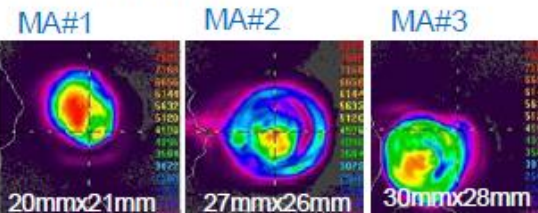
High Power EUV Light Source



Pulse waveform

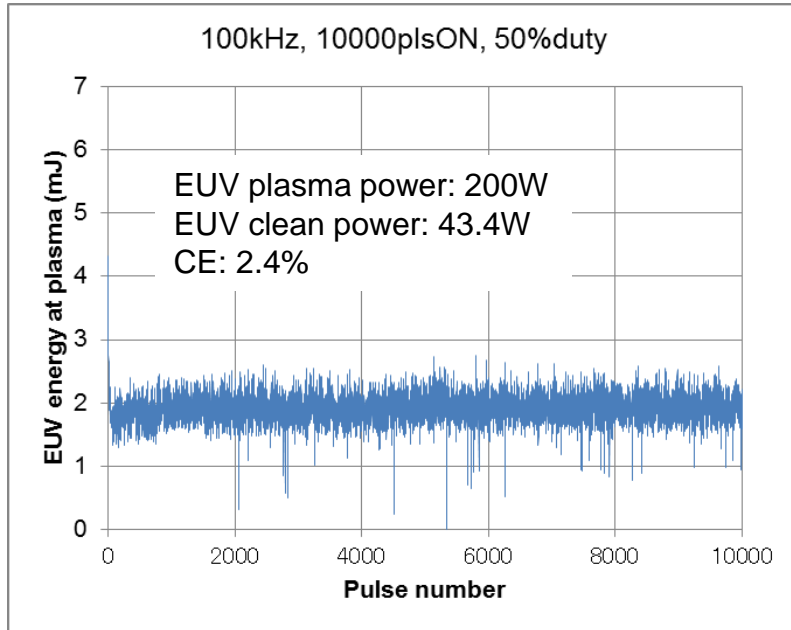


Beam Profile

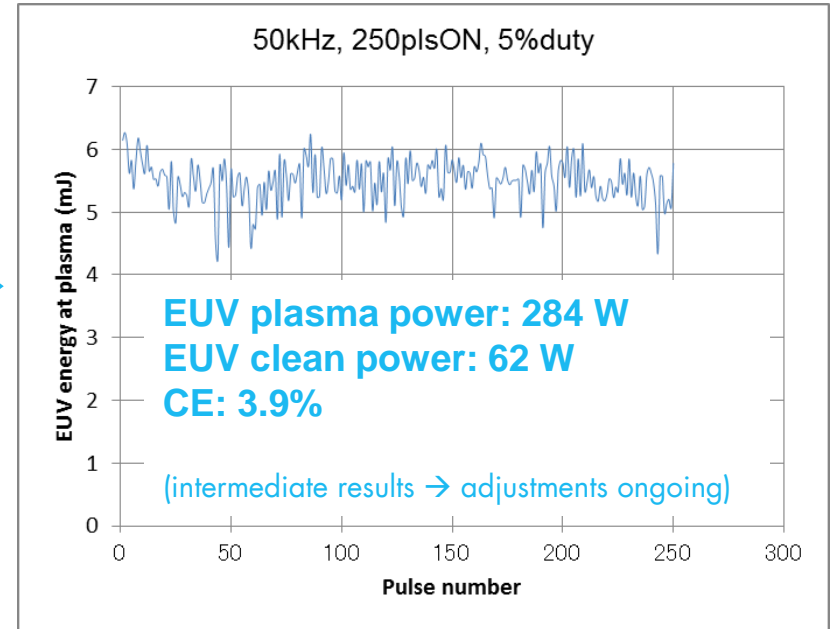


High Power EUV Light Source

2014 Jan



2014 May



AGENDA

- Key Technical Points of EUV LPP Light Source
 - » Issues of EUV Light Source Power
 - » History of LPP Technology
- Gigaphoton's LPP Light Source Concept
 - » Droplet Generator
 - » Pre-pulse Technology
 - » Collector Mirror and IR Reduction Technology
 - » Debris Mitigation Technology
- Gigaphoton's High Power LPP Light Source System Development
 - » Debris Mitigation Technology Update
 - » Output Power Update
- Power-up Scenarios of HVM EUV Light Sources
- Summary

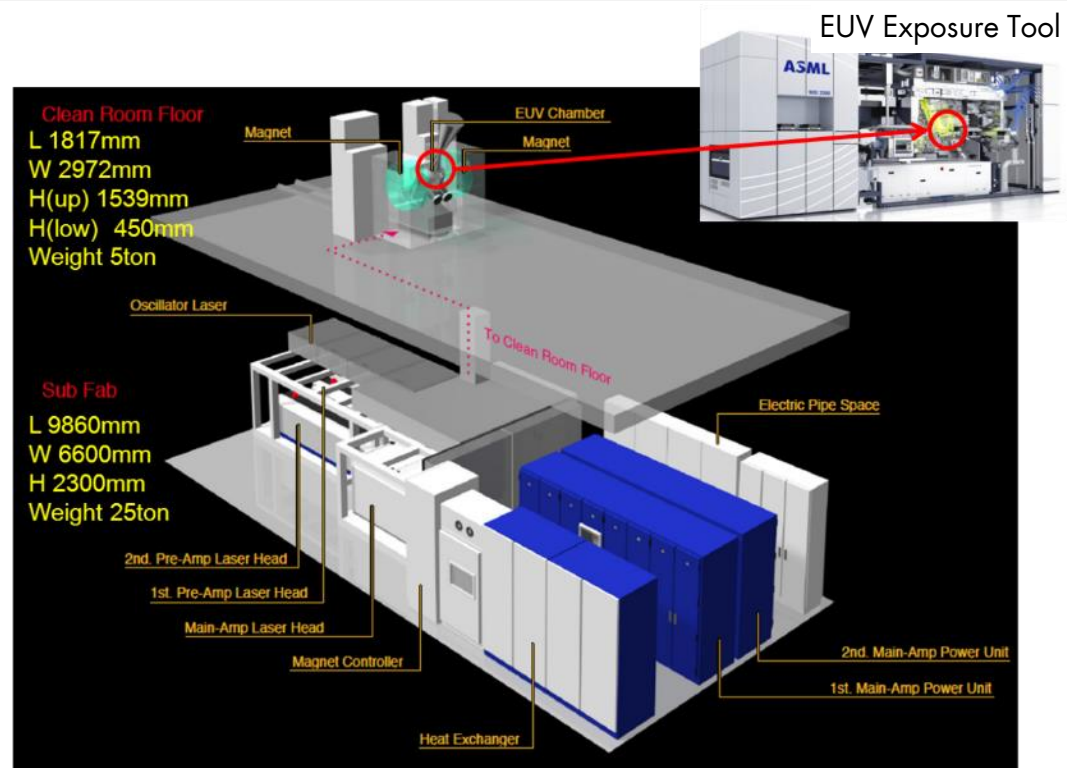
Power-up Scenario of HVM Sources

Layout of 250W EUV light source

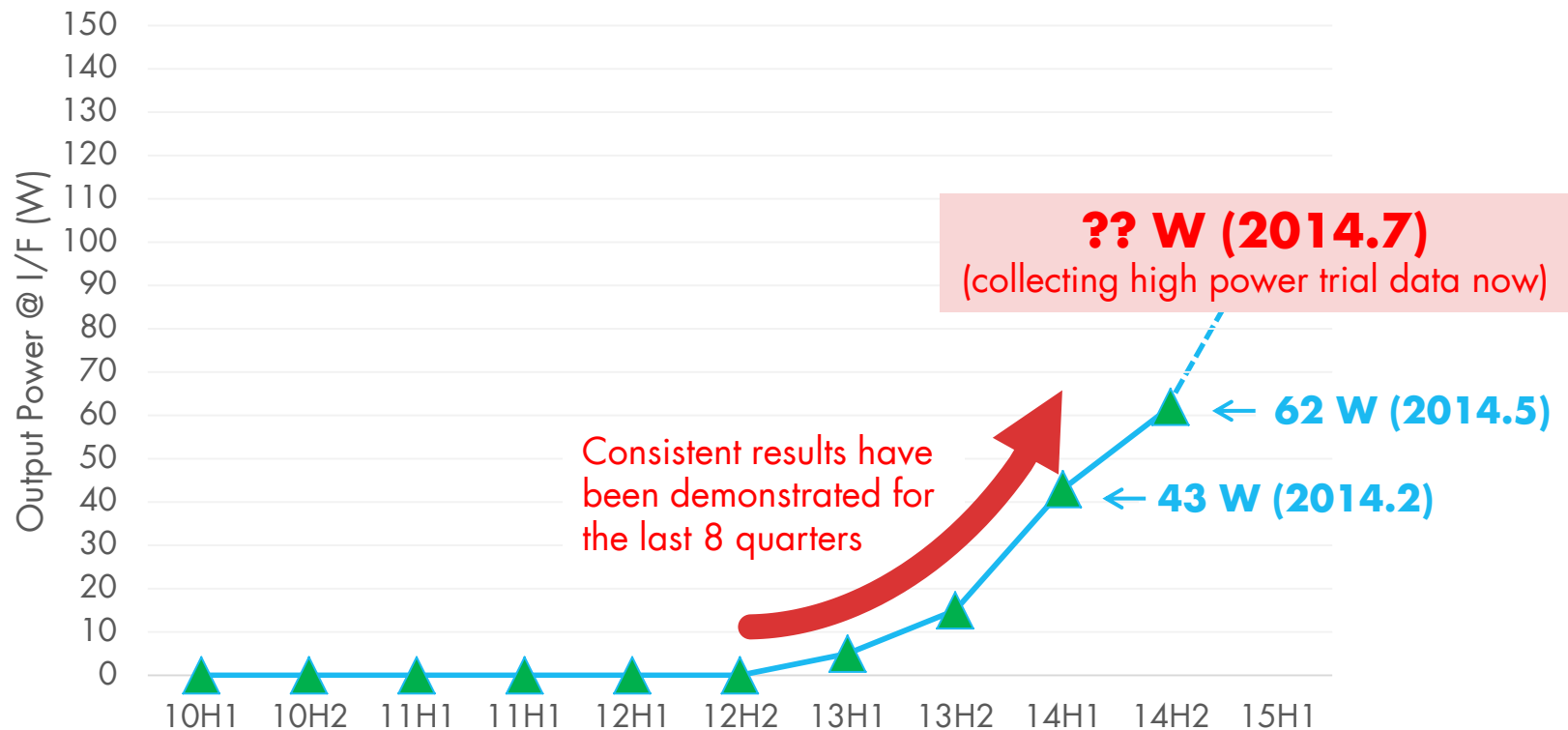
First HVM EUV Source

- Gigaphoton is developing 250W EUV source
- Target is 2015

Operational specification (Target)		HVM Source	
Performance	EUV Power	> 250W	
	CE	> 4.0 %	
	Pulse rate	100kHz	
	Availability	> 75%	
Technology	Droplet generator	Droplet size	< 20mm
	CO2 laser	Power	> 20kW
	Pre-pulse laser	Pulse duration	psec
	Debris mitigation	Magnet, Etching	> 15 days (>1500Mpls)

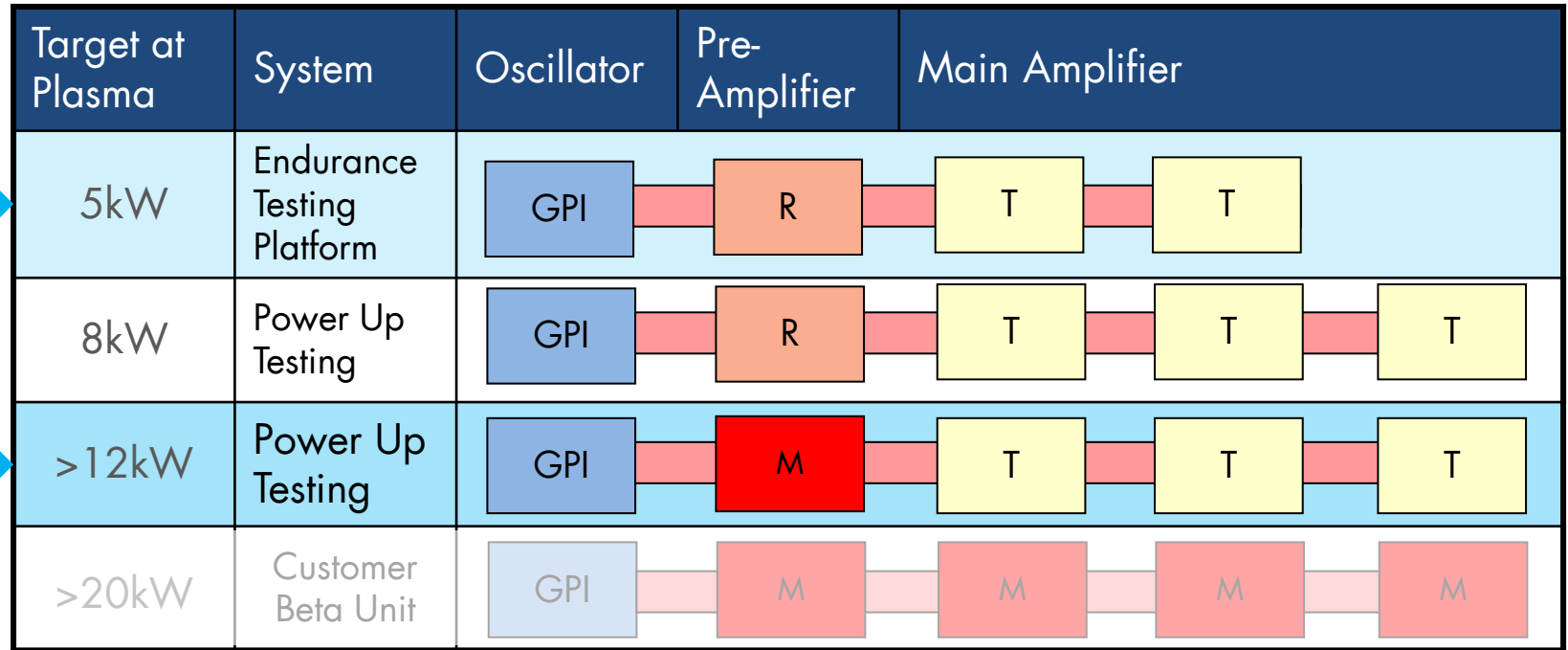


Power-up Scenario of HVM Sources



Power-up Scenario of HVM Sources

Next target is 12 kW by upgrading the pre-amplifier (installation is on going now)



Validated performances at system

Power-up Scenario of HVM Sources

We are achieving **solid** and **steady** progress towards realizing our HVM EUV source

	New Data Available Very Soon!			Next Target	
EUV clean power	25W	43W	??W	150W	250W
Target	2013, Q4	2014, Q1	2014, Q2	2014, Q4	2015, Q2
CO ₂ power at plasma	5kW	8kW	14kW	>14kW	> 20kW
CE	2.5%	3%	??%	4%	> 4.5%
Plasma to IF clean	21.7%	21.7%	??%	26.7%	26.7%
CO ₂ laser	2 main amp. system	3 main amp. system	Mitsubishi pre. amp.	Mitsubishi pre. amp	Mitsubishi main amp. system
Pre-pulse laser	ps-laser	ps-laser	ps-laser	ps-laser	ps-laser
Collector mirror	V3 type	V3 type	V5 type	V5 type	V5 type

 Performance was confirmed at 100kHz system

 Performance was confirmed at 10Hz source or parts level

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Summary

- Component technology progress
 - » 20 μm droplets at 100 kHz operation was successfully ejected by downsized nozzle.
 - » Development of new generation collector mirror with IR reduction technology is on going.
- Proto #2 LPP source
 - » Intermediate results showing 62 W EUV clean power @ I/F at 50 kHz operation was seen in May. EUV energy drop in high repetition rate operation is currently undergoing improvements.
 - » High conversion efficiency (CE) of 3.9% at 50 kHz operation was seen using picosecond pre-pulse laser.
- Proto #1 LPP source
 - » Promising results from debris mitigation performance tests were obtained using 20 μm droplets.
 - » Next step is to eliminate the Sn depositions caused by the ion catcher.
- Power-up scenario of HVM source
 - » Plan to upgrade CO_2 power to 20 kW is in progress.
 - » New >20 kW CO_2 laser amplifier is under development in co-operation with Mitsubishi electric.
 - » Target shipment of first customer beta LPP light source unit is 2015.

Acknowledgements

Thanks for your co-operation:

Mitsubishi electric CO₂ laser amp. develop. team: Dr. Yoichi Tanino*, Dr. Junichi Nishimae, Dr. Shuichi Fujikawa and others.

** The authors would like to express their deepest condolences to the family of Dr. Yoichi Tanino who suddenly passed away on February 1st, 2014. We are all indebted to his incredible achievements in CO₂ amplifier development. He will be missed very much.*

Collector mirror suppliers – especially **Rigaku** for providing us with useful data

Dr. Akira Endo :**HiLase Project (Prague)** and Prof. Masakazu Washio and others in **Waseda University**

Dr. Kentaro Tomita, Prof. Kiichiro Uchino and others in **Kyushu University**

Dr. Jun Sunahara, Dr. Katsunori Nishihara, Prof. Hiroaki Nishimura, and others in **Osaka University**

Thanks for you funding:

EUV source development funding is partially support by **NEDO in JAPAN**

Thanks to my colleagues:

EUV development team of Gigaphoton; Hiroaki Nakarai, Tamotsu Abe, Takeshi Ohta, Krzysztof M Nowak, Yasufumi Kawasuji, Hiroshi Tanaka, Yukio Watanabe, Tsukasa Hori, Takeshi Kodama, Yutaka Shiraishi, Tatsuya Yanagida, Tsuyoshi Yamada, Taku Yamazaki, Takashi Saitou and other engineers.



Thank You